Notice of References Cited Application/Control No. 10/686,539 Applicant(s)/Patent Under Reexamination BAIK ET AL. Examiner Allen T. Cao Applicant(s)/Patent Under Reexamination BAIK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,028,747 A	02-2000	Lee, Sang-Jin	360/281.7
	В	US-5,764,442	06-1998	Komatsu et al.	360/271.7
	С	US-4,641,214	02-1987	Imanishi et al.	360/130.24
	D	US-5,463,506 A	10-1995	Mitsuyasu et al.	360/77.17
	E	US-5,317,466 A	05-1994	Hasegawa, Shinichi	360/271.7
	F	US-2001/0043442	11-2001	MAEMINE, KENJI	360/271.5
	G	US-2004/0042125 A1	03-2004	Matsui, Kiyoshi	360/271.5
	Н	US-6,369,991 B1	04-2002	Choi et al.	360/271.7
	1	US-4,875,110	10-1989	Kazama et al.	360/64
	J	US-4,564,876	01-1986	Takahashi et al.	360/291.6
	К	US-5,798,891	08-1998	Lee, Sang-Jin	360/271.7
	L	US-			
	М	US-		·	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country .	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	·W	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707,05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign: